Search Notes		
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Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/624,627	TRAN, LUAN C.	
Examiner	Art Unit	
Jennifer M. Kennedy	2812	

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438	194-196	2/16/2005	JMK
438	217-219	2/16/2005	JMK
438	229-233	2/16/2005	JMK
438	585-587	2/16/2005	JMK
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